

# The Role of Frustration in Magnetism of $\text{Ge}_{1-x}\text{Cr}_x\text{Te}$ Semimagnetic Semiconductor

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This article was originally published on May 2011 (online on April 2011) with an incorrect version of Fig. 1. The authors apologize for this error. The correct version of Fig. 1 appears below.

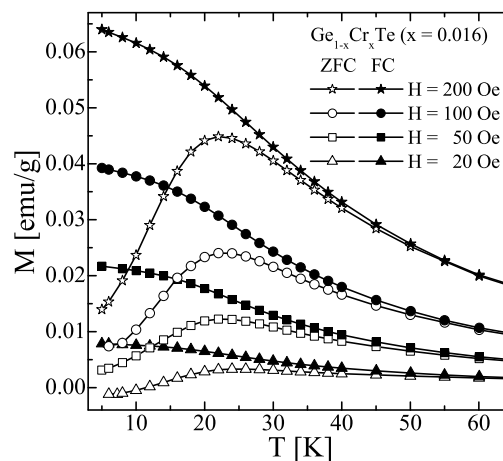


Fig. 1. The magnetization  $M$  as a function of temperature for selected  $\text{Ge}_{0.984}\text{Cr}_{0.016}\text{Te}$  crystal measured after cooling sample in the presence (FC) and the absence (ZFC) of the external magnetic field  $H$  having four different amplitudes.